Docket No. 741124-79

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of	)	
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Michael HERMANN	)	Group Art Unit: 2872
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Application No.: 09/817,797	)	Examiner: Audrey Y. Chang
	:	
Filed: March 27, 2001	)	Confirmation No. 8356
	:	
For: DEVICE FOR QUANTITATIVE ASSESSMENT OF THE ALIGNED POSITION OF TWO MACHINE PARTS, WORKPIECES OR THE LIKE:	)	

RESPONSE TO NOTICE OF NON-COMPLIANT APPEAL BRIEF

Mail Stop Appeal Brief-Patents
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Notice of Non-Compliant Appeal Brief mailed December 17, 2007, appended hereto are corrected *Status of Claims* and *Summary of Claimed Subject Matter* sections.

Status of Claims.

Claims 1, 3 & 4 stand rejected and form the subject matter of this appeal. Claim 2 has been cancelled. No other claims exist.

Summary of Claimed Subject Matter.

Inasmuch as claims 1, 3 & 4 are similar in many respects and there patentability is argued jointly below, a consolidated summary of the claimed subject matter is presented below with only key differences of claim 3 being indicated.

A device for measuring or evaluating the relative angular offset position of two elements with respect to each other (Fig. 3), comprising a collimated light source 20 for producing at least one light beam (25) is connected to a first of the two elements at a known location (paragraph [0018], second sentence, page 5) and a first two-dimensionally readable optoelectronic sensor (110) and at least one second two-dimensionally readable optoelectronic sensor (120) connected to a second of the two elements, each of which is in a fixed relative alignment with respect to each other (paragraph [0018], third sentence, page 5) at a known location such that a portion of the at least one light beam (25) is incident on a surface of an optoelectronically active layer of the first optoelectronic sensor (110, paragraph [0018], last sentence, page 5) and is reflected by the surface of the optoelectronically active layer as a light beam (125) directly onto a surface of the at least one second two-dimensionally readable optoelectronic sensor (120, Fig. 3). An electronic means for receiving output signals from each of the optoelectronic sensors representing the coordinates at which the at least one light beam and reflected portion of the at least one light beam are detected on each respective sensor of the optoelectronic sensors, processing the signals, and computing the relative angular offset position of the two elements with respect to each other based on the coordinates detected (paragraph [0019], spanning pages 5 & 6). In alternative embodiments to which claim 3 is directed, a portion of the light beam incident on the first two-dimensionally readable optoelectronic sensor is reflected as a plurality of light beams (125, 225, 325; Fig. 4) in a folded beam path (125, 125'; Fig. 5 modification of Fig. 4) by a surface of an optoelectronically active layer of the first optoelectronic sensor (110) directly

onto the second two-dimensionally readable optoelectronic sensor (see, paragraphs [0021] and [0022], page 6).

Respectfully submitted,

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